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	Nota di contenuto	Chapter1: A Preliminary Taxonomy for Machine Learning in VLSI CAD Chapter2: Machine Learning for Compact Lithographic Process Models Chapter3: Machine Learning for Mask Synthesis Chapter4: Machine Learning in Physical Verification, Mask Synthesis, and Physical Design Chapter5: Gaussian Process-Based Wafer-Level Correlation Modeling and its Applications Chapter6: Machine Learning Approaches for IC Manufacturing Yield Enhancement Chapter7: Efficient Process Variation Characterization by Virtual Probe Chapter8: Machine learning for VLSI chip testing and semiconductor manufacturing process monitoring and improvement Chapter9: Machine Learning based Aging Analysis Chapter10: Extreme Statistics in Memories Chapter11: Fast Statistical Analysis Using Machine Learning Chapter12: Fast Statistical Analysis of Rare Circuit Failure Events Chapter13: Learning from Limited Data in VLSI CAD Chapter14: Large-Scale Circuit Performance Modeling by Bayesian Model Fusion Chapter15: Sparse Relevance Kernel Machine Based Performance Dependency Analysis of Analog and Mixed-Signal Circuits

	Chapter16: SiLVR: Projection Pursuit for Response Surface Modeling Chapter17: Machine Learning based System Optimization and Uncertainty Quantification of Integrated Systems Chapter18: SynTunSys: A Synthesis Parameter Autotuning System for Optimizing High-Performance Processors Chapter19: Multicore Power and Thermal Proxies Using Least-Angle Chapter20: A Comparative Study of Assertion Mining Algorithms in GoldMine Chapter21: Energy- Efficient Design of Advanced Machine Learning Hardware.
Sommario/riassunto	This book provides readers with an up-to-date account of the use of machine learning frameworks, methodologies, algorithms and techniques in the context of computer-aided design (CAD) for very- large-scale integrated circuits (VLSI). Coverage includes the various machine learning methods used in lithography, physical design, yield prediction, post-silicon performance analysis, reliability and failure analysis, power and thermal analysis, analog design, logic synthesis, verification, and neuromorphic design. Provides up-to-date information on machine learning in VLSI CAD for device modeling, layout verifications, yield prediction, post-silicon validation, and reliability; Discusses the use of machine learning techniques in the context of analog and digital synthesis; Demonstrates how to formulate VLSI CAD objectives as machine learning problems and provides a comprehensive treatment of their efficient solutions; Discusses the tradeoff between the cost of collecting data and prediction accuracy and provides a methodology for using prior data to reduce cost of data collection in the design, testing and validation of both analog and digital VLSI designs. From the Foreword As the semiconductor industry embraces the rising swell of cognitive systems and edge intelligence, this book could serve as a harbinger and example of the computing era to the cognitive one, it behooves us to remember the success story of VLSI CAD and to earnestly seek the help of the invisible hand so that our future cognitive systems are used to design more powerful cognitive systems. This book is very much aligned with this on-going transition from computing to cognition, and it is with deep pleasure that I recommend it to all those who are actively engaged in this exciting transformation. Dr. Ruchir Puri, IBM Fellow, IBM Watson CTO & Chief Architect IBM T_ I